



WinWay

Your Trusted Partner in Semiconductor Testing

TWSE:6515

Investor Presentation

2026.05.26

Safe Harbor Notice

This presentation may contain forward-looking statements. All statements, other than statements of historical facts, that address activities, events or developments that WinWay Technology Co., Ltd. expects or anticipates will or may occur in the future (including but not limited to projections, targets, estimates and business plans) are forward-looking statements.

WinWay's actual results or developments may differ materially from those indicated by these forward-looking statements as a result of various factors and uncertainties, including but not limited to market demand, price fluctuations, competition, change in legal, government policies, financial market conditions, and other risks and factors beyond our control.

This presentation does not undertake any obligation to publicly update any forward-looking statements to reflect events or circumstances after the date on which any such statement is made or to reflect the occurrence of unanticipated events.

Company Information

**Kaohsiung
Headquarter**

Founded

2001.4 .10

Capital Stock

NTD 360,416,420

Employees

1408

Chairman & CEO

Mark Wang

Business Operation

Design, manufacture, sale and service of test interface products

Registered Address

No.68, Chuangyi S. Rd, Nanzi Dist.
Kaohsiung City, Taiwan



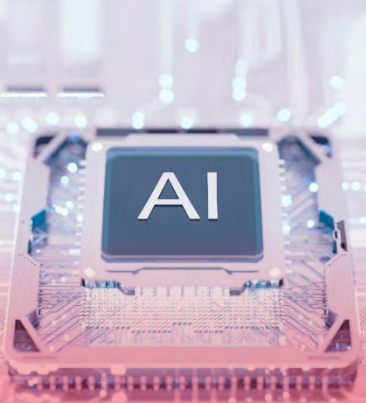
USA Branch Office



Hsinchu Branch Office



Company Vision




Innovation

We deliver the best possible test tooling solutions to our customers through technological innovation.



Quality

We exceed customers' quality requirements by offering cost-effective total solutions and on-time delivery worldwide.



Service

We strive to become the world's leading professional testing service provider in all phases of IC testing.

Agenda

Global Presence

Industry Trend

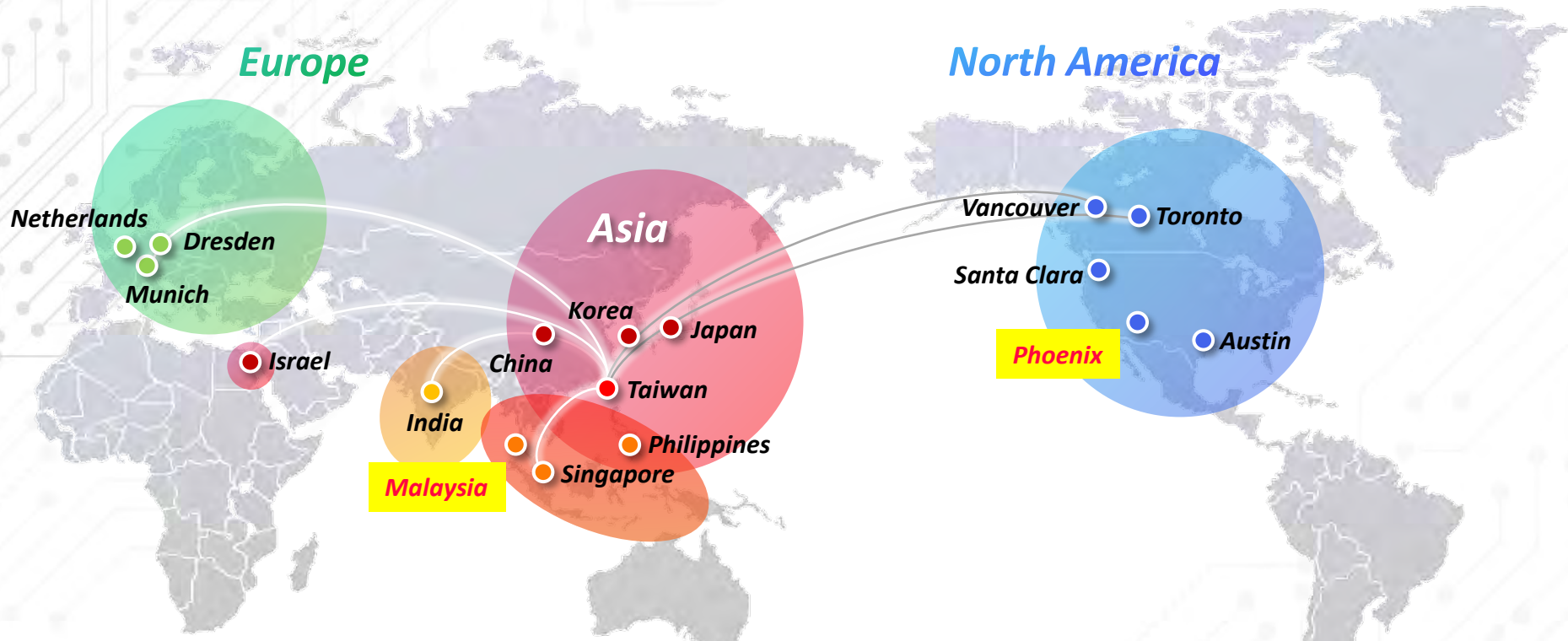
Financial Performance

R&D Innovation

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11011 001 1101 01  
100 110101 000110  
11 01110 01 11010  
0110 11 01 10 100
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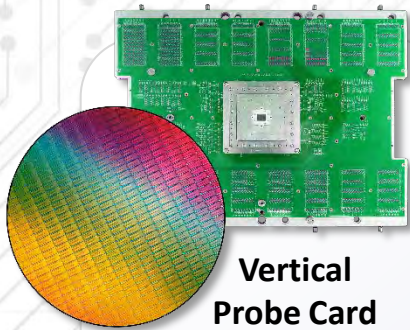
Global Presence

Global Service & Support Network

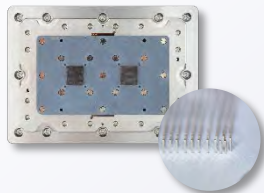


KH Spring Probe	KH Plant	Hsinchu Plant	Suzhou Plant	Renwu Plant
Spring Probe for Socket	Coaxial Socket HyperSocket™	Vertical Probe Card MEMS Probe Card	Coaxial Socket	Coaxial Socket

Your Trusted Partner in Semiconductor Testing



Vertical Probe Card



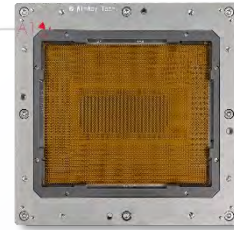
MEMS Probe Card



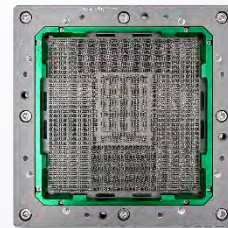
Coaxial Socket



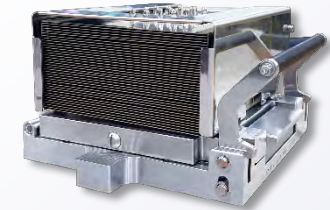
PoP Socket



HyperSocket™



Coaxial Socket



Production Burn-in Socket

Wafer Sort

Final Test

SLT & SFT

Functional Burn-in

DFT Design For Testing **DFM** Design For Manufacturing

Worldwide Customer

First 4 Months of 2026

North American
81%

China
7%

Taiwan
12%



Top10 Customers

90%

- AI
- HPC
- ASIC
- CPU
- GPU
- AP

Active Customers

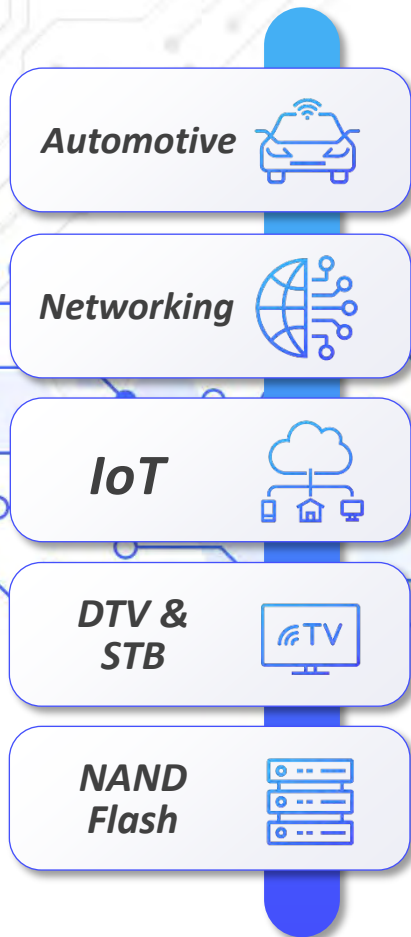
200+

- IC Design
- CSP
- Foundry
- ASIC
- OSAT
- IDM

Bolstered by Advanced Technology

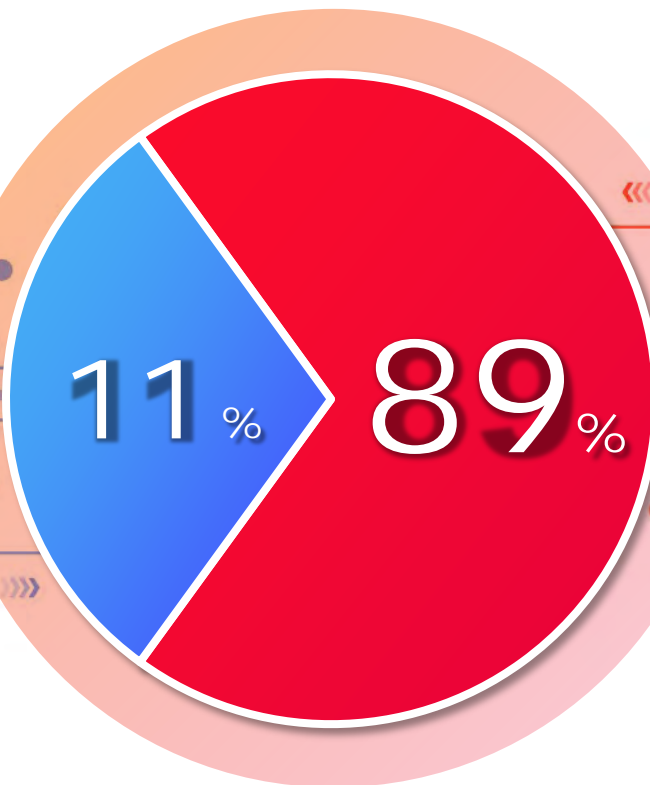
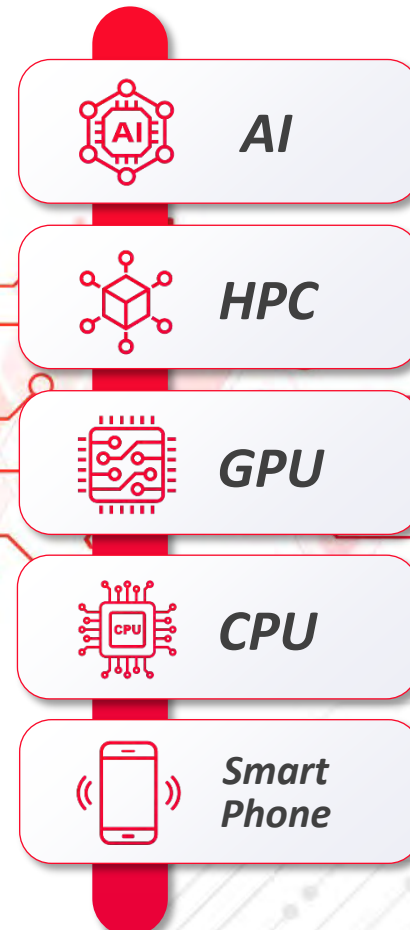
First 4 Months of 2026

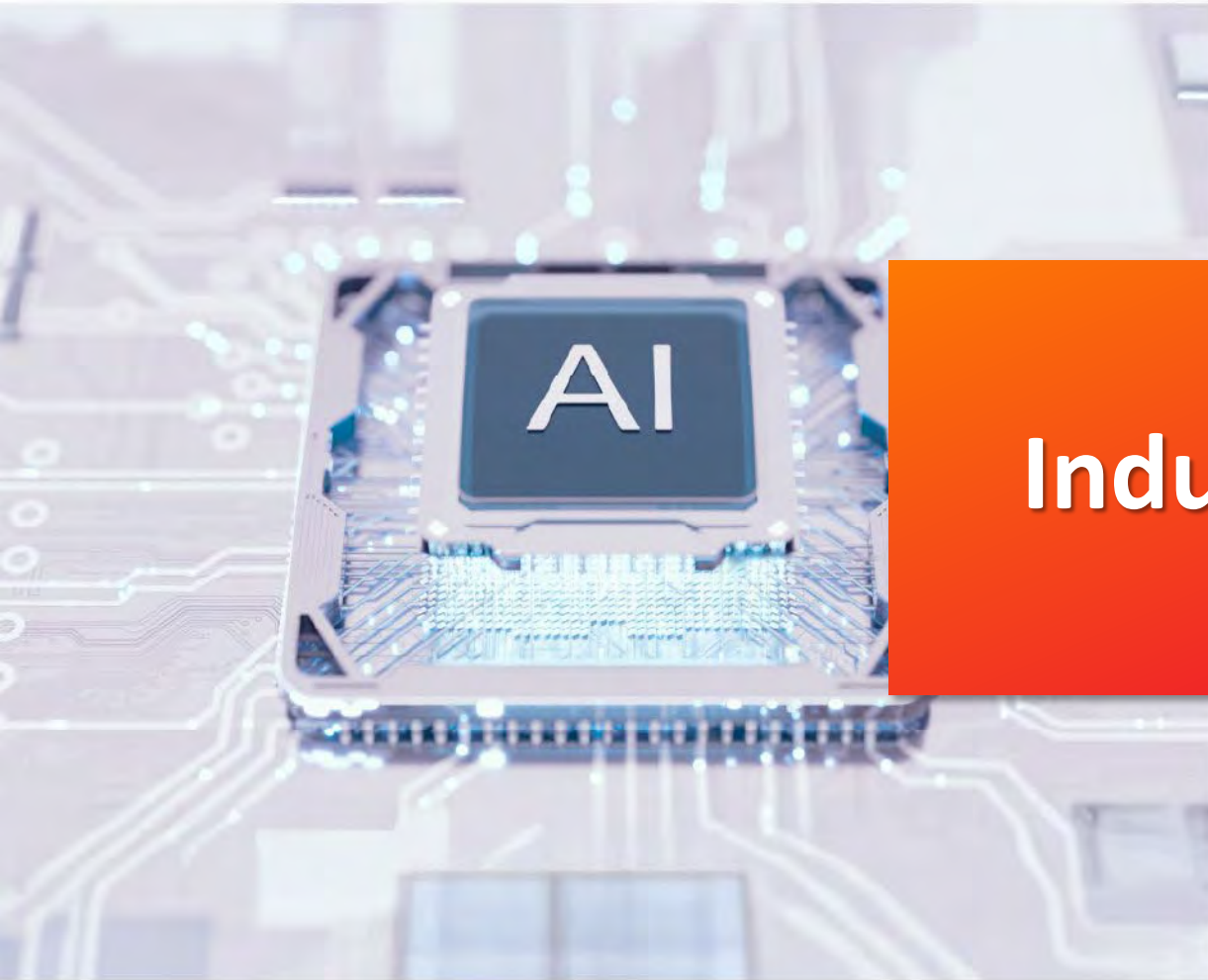
Mature Node



Advanced Node

7nm (or equivalent node) and below





Industry Trend

AI Advances the Value Chain of Tomorrow

Applications

- AI Agent
- LLM / Gen AI
- AI PC
- Humanoid Robot
- Smart Factory
- Self-driving car
- AR/VR
- Digital Twins
- Smart City

Models

- AI Framework
- Foundation Model
- MLOps / Platform
- AI Training Platform

Infrastructure

- AI Factory
- Liquid Cooling
- Hyperscale Datacenter
- Optical Network

Chips

- GPU
- XPU
- AI ASIC
- CPU
- CoWoS / SoIC
- HBM
- Chiplet
- CPO / CPC

Energy

- Power Delivery
- Green Energy
- Electric power



Source : NVIDIA

Driving Force for AI

Agentic AI



Collaborative Robots



AI
PC & Phone



Edge
Computing



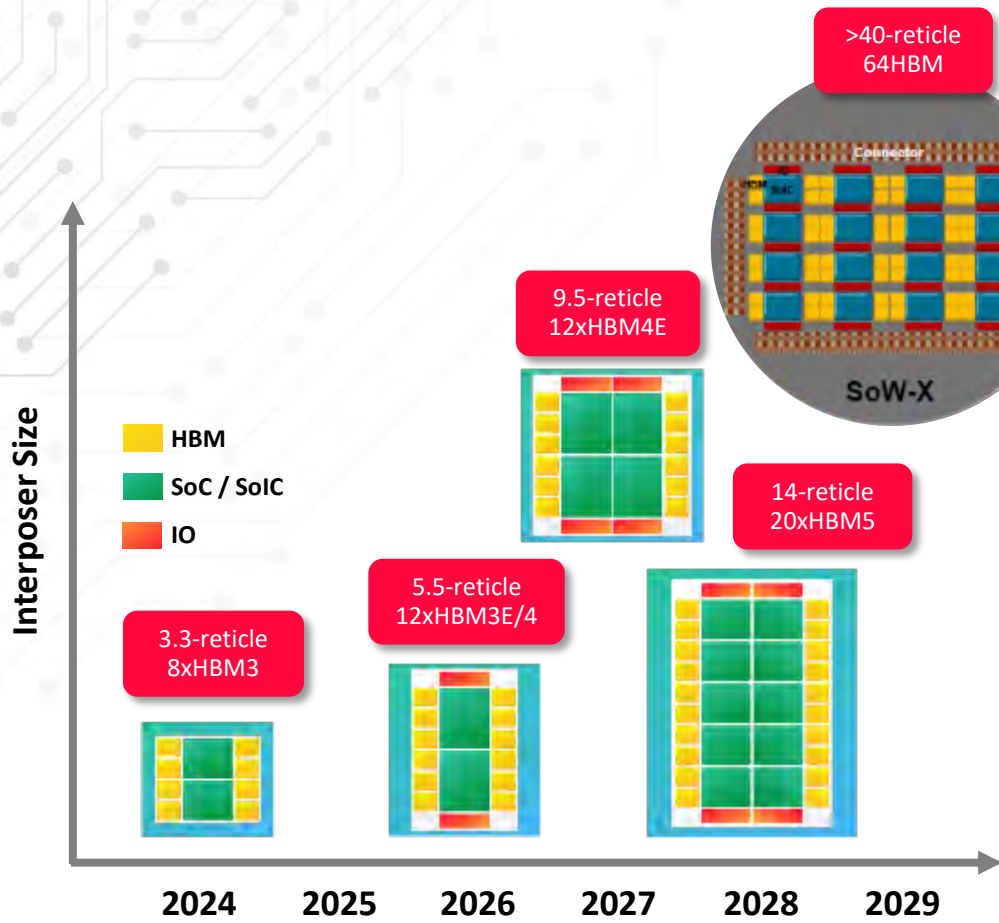
High Speed
Networking



Data Center

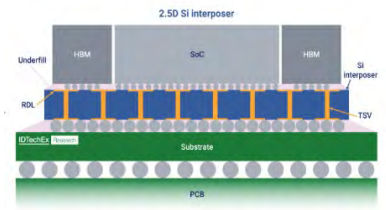


Performance Breakthrough: Evolution of Advanced Packaging

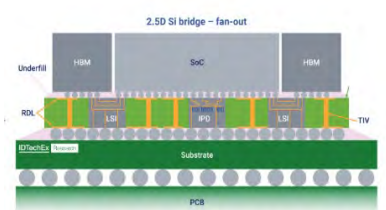


Source : TSMC

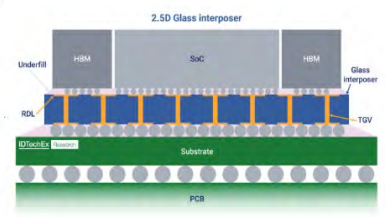
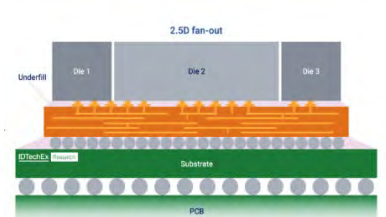
Si-based Interposer



Organic-based Interposer

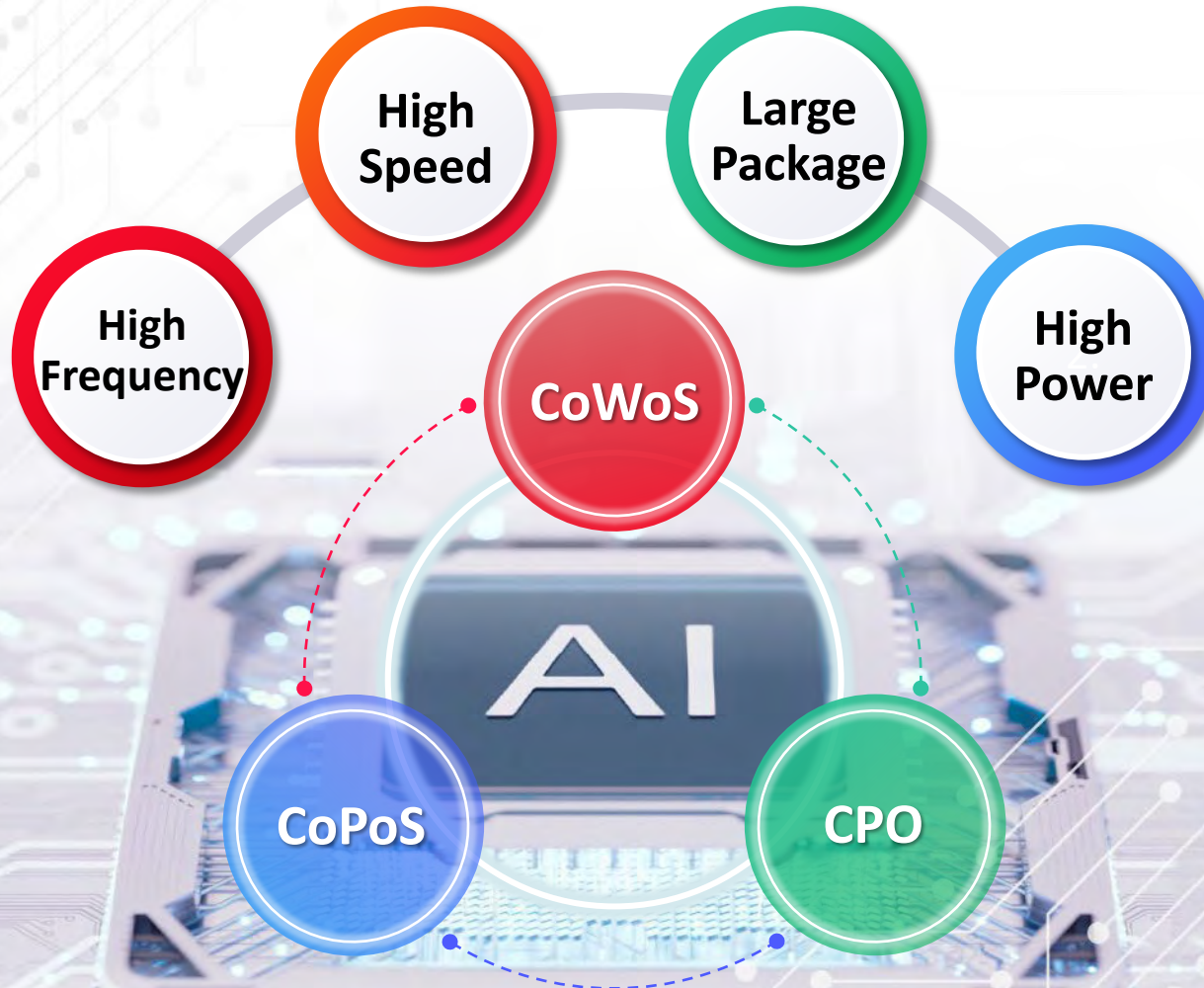


Glass-based Interposer



Source : IDTechEx Research

High Performance Testing Driven by Advanced Packaging



Opportunities for Semi Test Interface

Wafer Sort (CP - Circuit Probe)



• K.G.D

Cobra Probe Head

MEMS Probe Head

FT(Final Test)

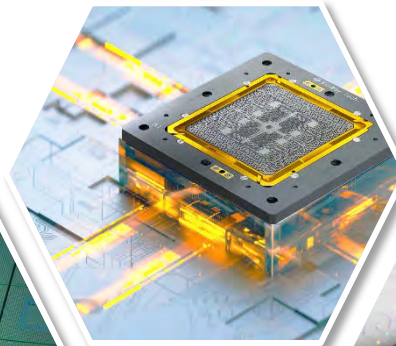


- CPO/CPC substrate
- Optical Engine
- WMCM/SiP/MoP

Coaxial Socket

PoP Socket

SLT (System Level Test) , SFT

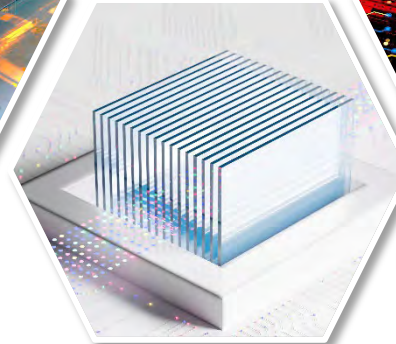


- 2.5D&3D PKG
- WMCM/SiP/MoP
- CPO Module

HyperSocket™

Coaxial Socket

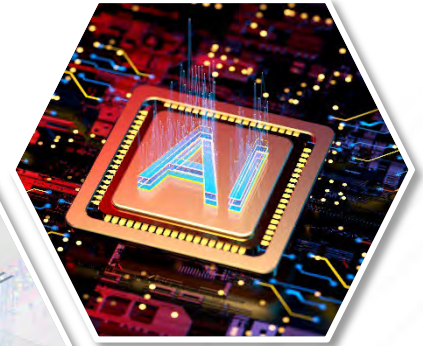
Functional Burn-in



Production Burn-in

Functional Burn-in

(Thermal System)

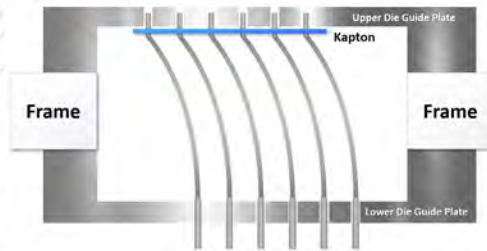


Liquid Cooling
HyperSocket™

Active Thermal
Controller

Greater Importance on Chip Probing

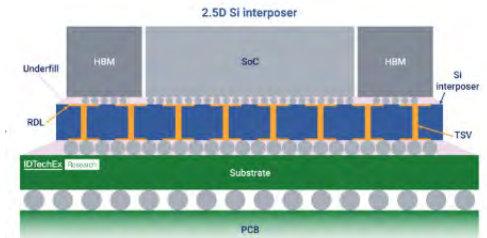
At Speed Test and K.G.D



Cobra



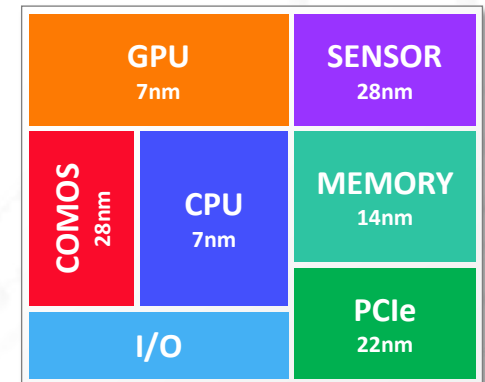
MEMS



Source : IDTechEx Research

Pin Count	Less, limited to probe force design	★ Higher (More flexible to design)
CCC(A)	2.2 @ 4mil probe diameter	★ 2.2 @ 3mil probe diameter
High Speed	32G	★ 112G
Force(g)	2~25	★ 1.5 ~ 4.5
Pitch (um)	80~200	★ 40~200
Operating Temp.	- 50°C to 150°C	★ - 50°C to 175°C

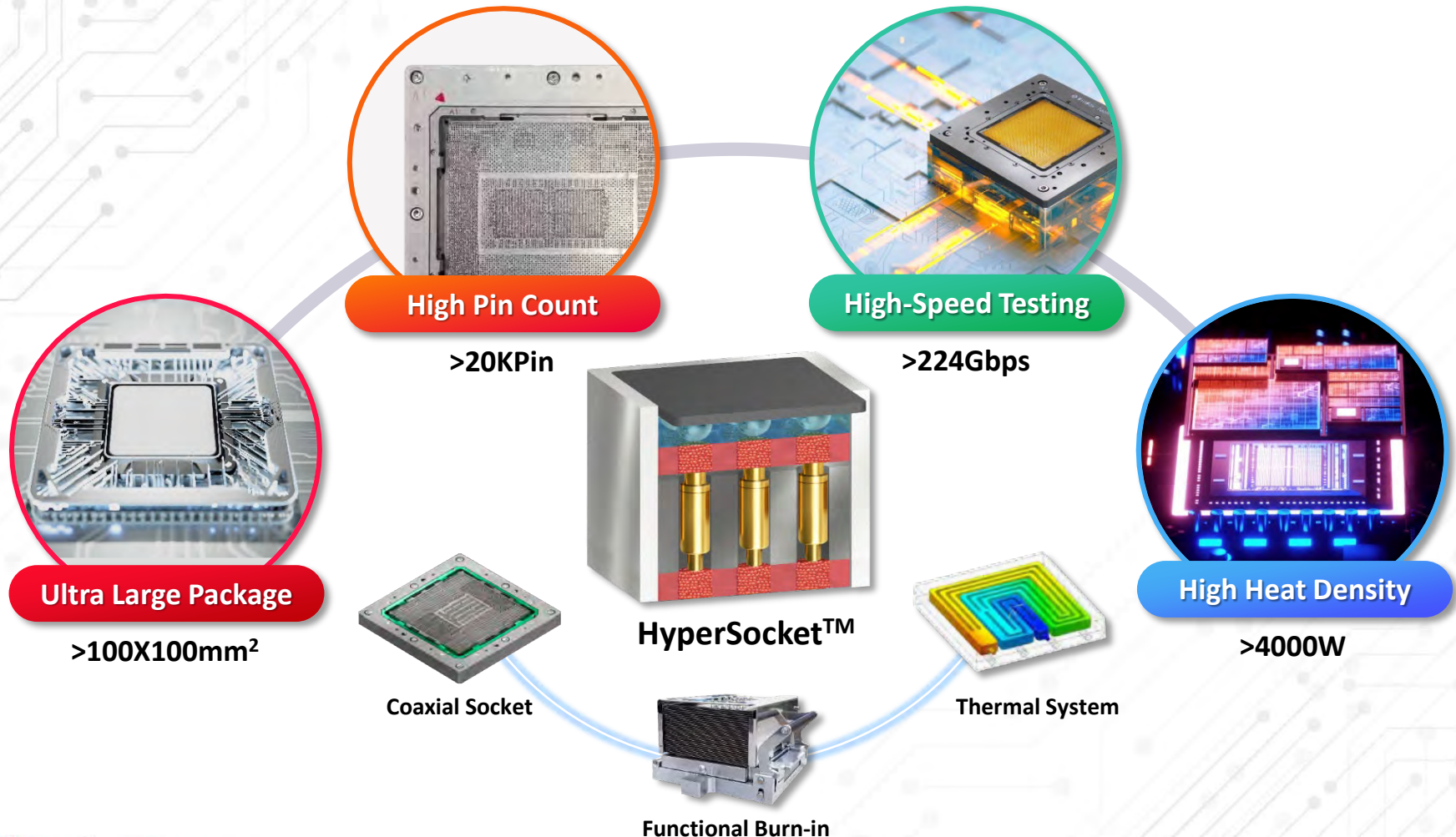
Chiplet Multiple Probe Card Demand



Source : Trend Force

Accelerated SLT Demand Driven by AI

Comprehensive solution for all test insertions





Financial Performance

Statements of Comprehensive Income

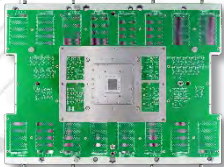
2025
Dividend
(NTD) **50**

2026

(NTD MILLION)	1Q26	4Q25	1Q25	1Q26 Over 4Q25	1Q26 Over 1Q25
Revenue	2,980	2,234	2,297	+33%	+30%
Gross Margin	43%	42%	49%	+1ppts	-6ppts
Operating Expenses	505	457	393	+11%	+29%
Operating Margin	26%	21%	32%	+5ppts	-6ppts
Net Income	699	483	613	+45%	+14%
Net Margin	24%	22%	27%	+2ppts	-3ppts
EPS (NTD)	19.54	13.53	17.21	+44%	+14%

Revenue by Product Mix

First 4 Months of 2026



Probe Card

27 %



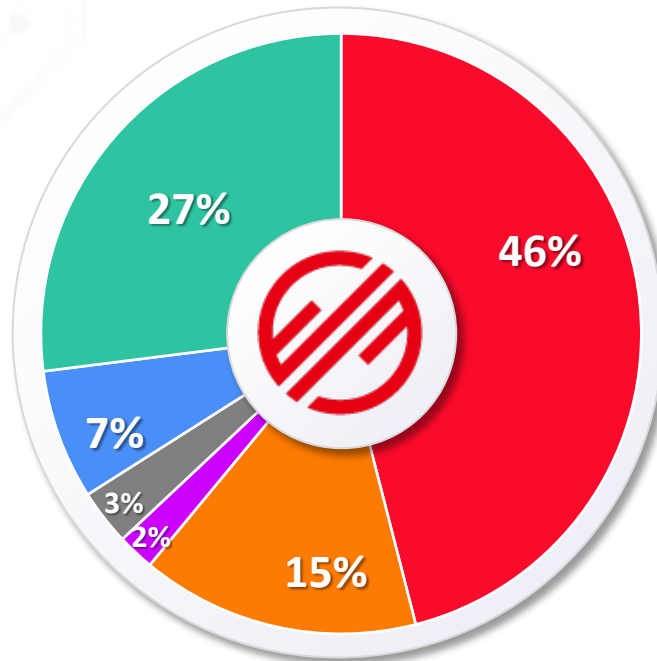
Contact Element

7 %



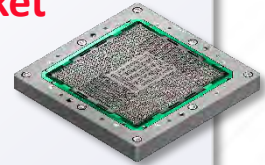
Others

3 %



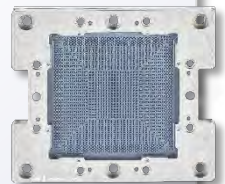
Coaxial Socket

46 %



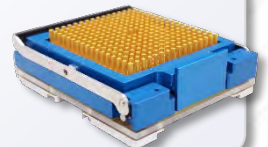
PoP & Plastic Socket

15 %



Burn-in Socket

2 %

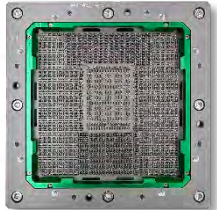


Revenue by End Market

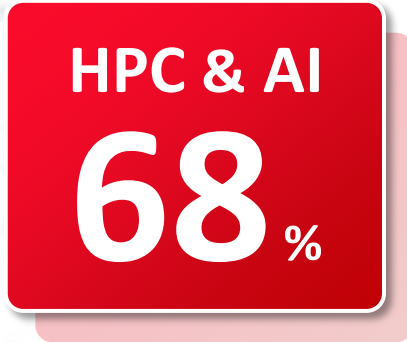
First 4 Months of 2026

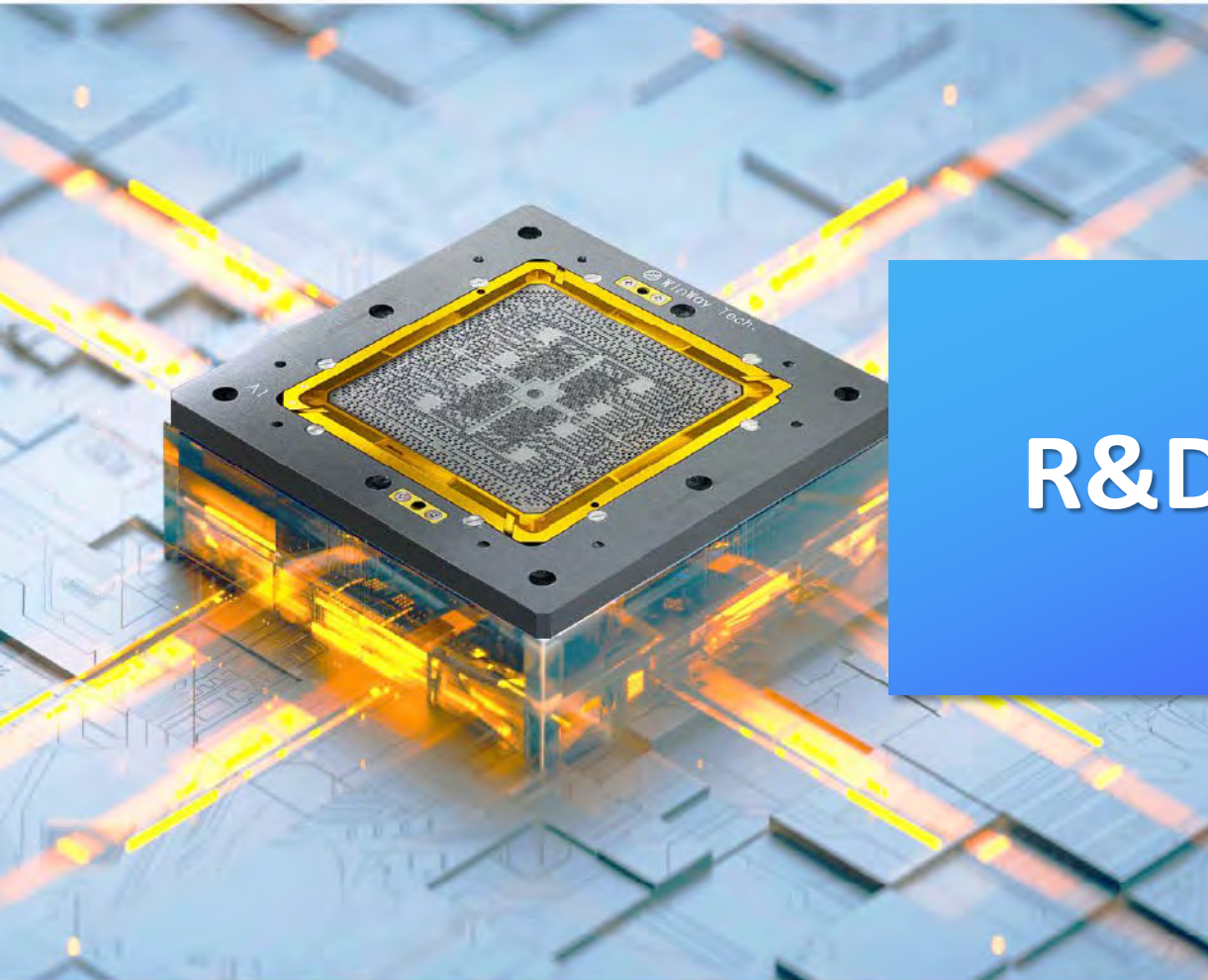


HyperSocket™



Coaxial Socket





R&D Innovation

Innovative Semiconductor Test Interface Solution

HyperSocket™-Dual Film

Patent NO.

TWI862047
TWI884802
TWI862191
TWI901161
TWI922268
TWI923382
CN220584352

Patent Pending

USA
Malaysia



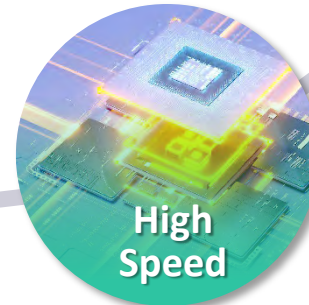
Large Package

- Larger contact area
- Improved heat dissipation
- Enhanced test stability



High Power

- Various current pathways
- Mitigating temperature rise



High Speed

- Full metal shielding, short-loop design
- Test speed above 224Gbps

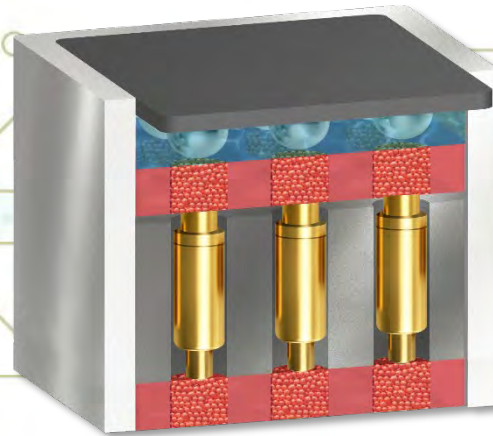


High Pin Counts

- Zero Pre-load design
- Reduced maintenance cost

Innovative Semiconductor Test Interface Solution

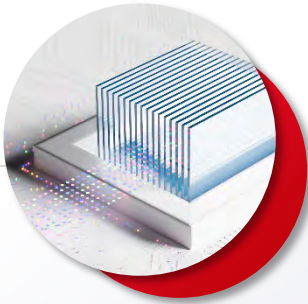
Liquid Cooling Socket



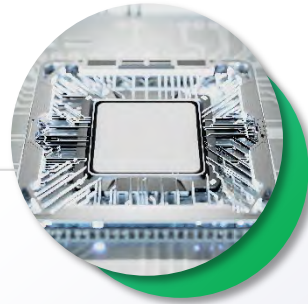
Patent NO.

TWI901181

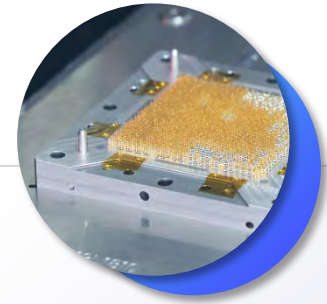
US12625162



**Extraordinary heat
dissipation**

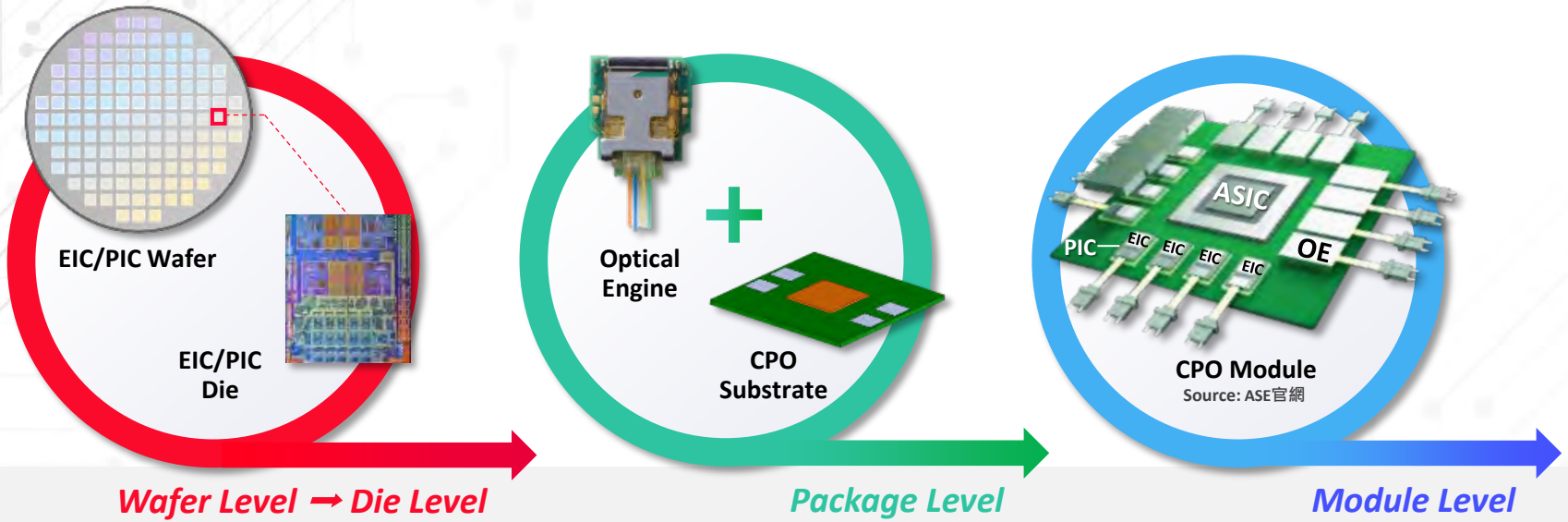


**Improved Test Stability
For Advanced Packaging**

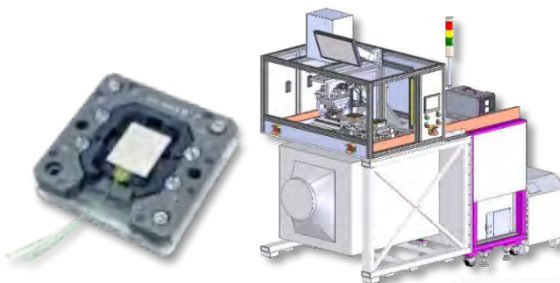


**Extend Spring
Probe Lifespan**

Co-Packaged Optics Test Solution

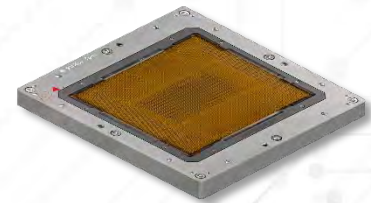


WLCSP Probe Head
(PIC & EIC Wafer test)



Optical and Electrical Test Socket
(Optical Engine)

Double Sided Probing System



HyperSocket™

High Power Thermal Solution

E-Flux6.0 3500W Liquid Cooling System



Accelerating Expansion Spring Probe Capacity



Cost Optimization

Balanced insourcing, better cost structure



Self-Sufficiency

Autonomy of critical process technology



Quality Assurance

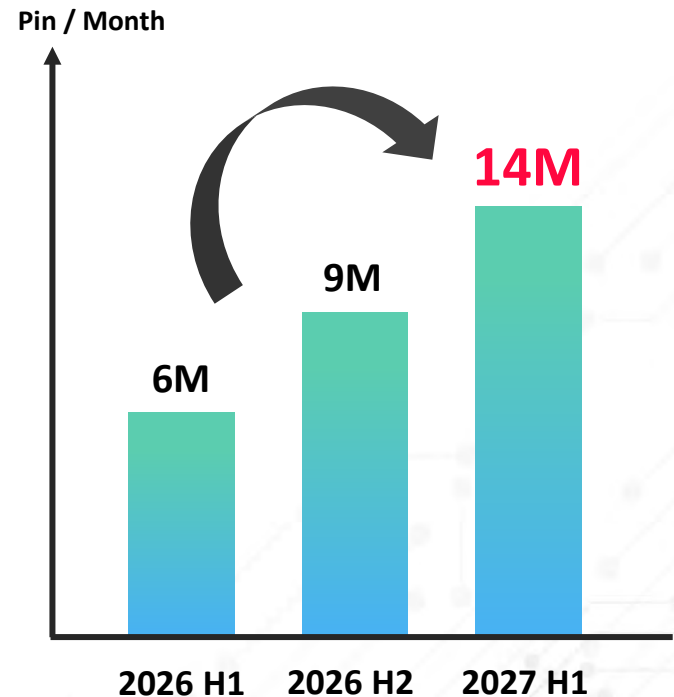
Greater customer experience



Operational Resilience

More flexible, agile lead time

WinWay Spring Probe Capacity



Accelerating Expansion Socket Capacity

Renwu Facility I

Operational from Apr. 2026

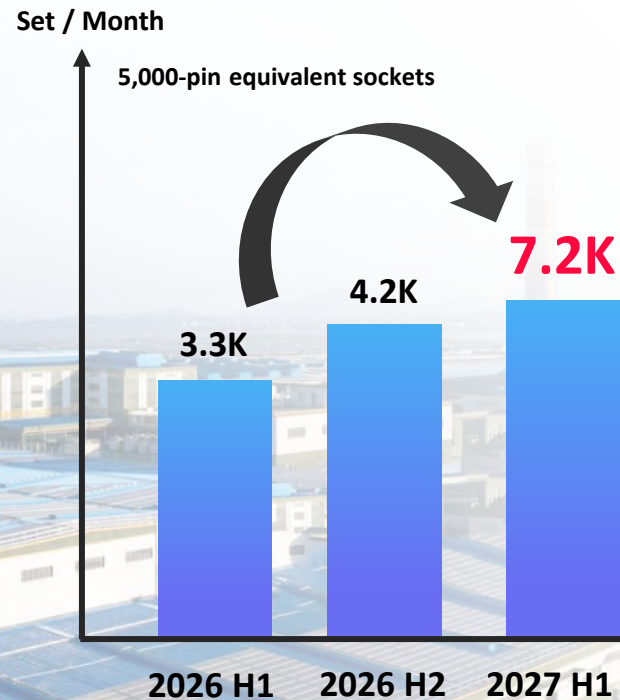
Renwu Facility II

Ground-breaking : 2026.5.29

Begin Operation : 2027 Q2

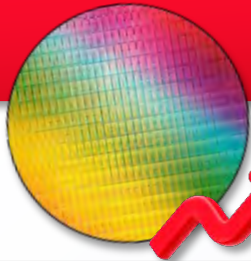
Total Area
Approx. **6300 ping**

WinWay Socket Capacity



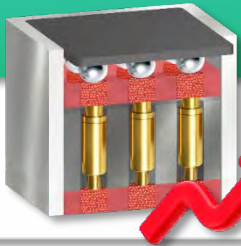
More Test Insertions

CoWoS、CoPoS、CPO



Fab and OSAT expansion drive equipment demand

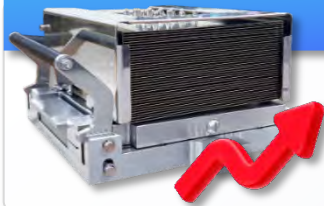
Longer and Longer Fab In-process Time



HyperSocket™ -DH

Bigger and Bigger Device Package

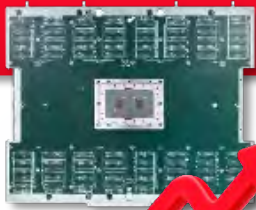
Higher and Higher Device Power Consumption



Functional Burn-In Requirement

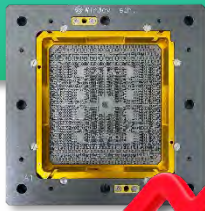
More Reliability Test Insertion

Significant Increase in Testing Time



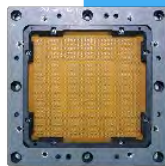
MEMS and Cobra Probe card

Longer Wafer Sort Test Time



Plastic, Coaxial and HyperSocket™

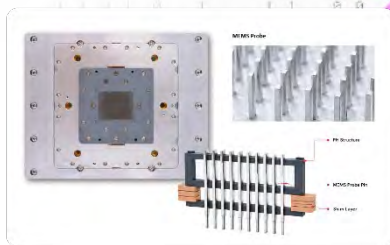
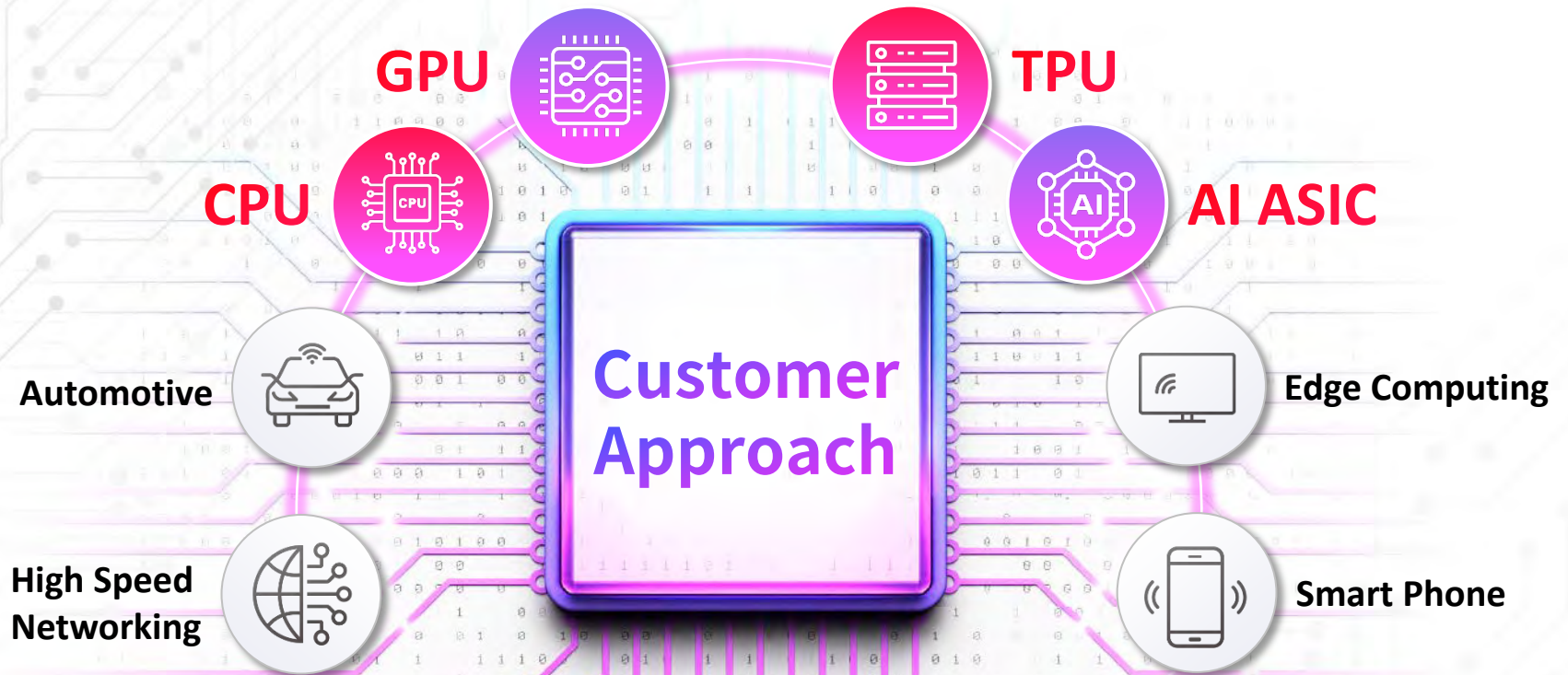
Longer FT (ATE) Test Time



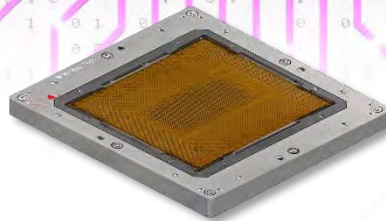
Coaxial and HyperSocket™

Longer SLT Test Time

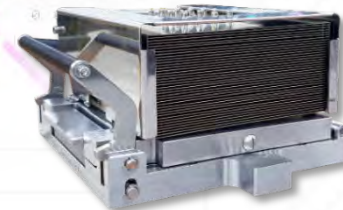
In for the Long Haul



MEMS Probe Card



HyperSocket™



Functional Burn-in



**Renwu Facility
Ground-breaking Ceremony**

2026.05.29

Renwu Industrial Park

No. 6, Renfa 6th Rd., Renwu Dist., Kaohsiung
City 814018, Taiwan



**2026 Annual
Shareholders' Meeting**

2026.06.17

Zhuang Jing Auditorium

No.600,Jiachang Rd., Nanzi Dist.,
Kaohsiung City 811636 , Taiwan

TWSE:6515

Q&A

TWSE:6515

**THANK
YOU**

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